



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Masaki Takakuwa et al.) Group Art Unit 2881

Appl. No. : 10/624,423

Filed : July 21, 2003

For : ELECTRON BEAM EXPOSURE

APPARATUS AND ELECTRON BEAM MEASUREMENT MODULE

Examiner : Paul M. Gurzo

Examiner : Paul M. Guizo

ELECTION & AMENDMENT

Hon. Commissioner of Patents and Trademarks Alexandria, VA 22313-1450

Dear Sir:

ELECTION:

This election is submitted in response to the office action mailed August 23, 2005 for the above-identified patent application.

The applicant elects, without prejudice, the invention group 2 directed to Figure 4 for further prosecution of this case.

Claims 8-13 are readable on the invention group 2.